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(54) **PROBE RETENTION KIT, AND SYSTEM AND METHOD FOR PROBING A PATTERN OF POINTS ON A PRINTED CIRCUIT BOARD**

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(52) **U.S. Cl.** **324/758**; 439/289

(58) **Field of Classification Search** None
See application file for complete search history.

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(57) **ABSTRACT**

A probe retention kit may include a plurality of probe retention devices, each having: (i) a base; (ii) a retention mechanism, coupled to the base, for mechanically coupling a probe substrate with the plurality of probe retention devices; and (iii) solder legs to be inserted into a printed circuit board, the solder legs having opposite ends that extend through the base and provide an alignment mechanism for receiving the probe substrate. Alternative probe retention devices, and systems and methods using same, are also disclosed.

7 Claims, 5 Drawing Sheets

